Triacs logic level

BT131 series D and E

GENERAL DESCRIPTION

Passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

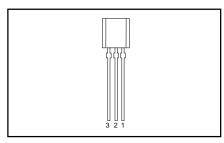
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
	BT131- BT131-	600D 600E	800D 800E	
V_{DRM}	Repetitive peak off-state			V
21	voltages	600	800	A
I _{T(RMS)}	RMS on-state current	1	1	
l I _{TSM}	Non-repetitive peak on-state			A
	current	12.5	12.5	

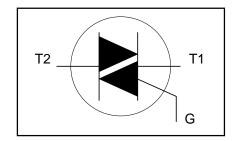
PINNING - TO92

PIN	DESCRIPTION		
1	main terminal 2		
2	gate		
3	main terminal 1		

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
V_{DRM}	Repetitive peak off-state voltages		-	-600 600 ¹	-800 800	V
I _{T(RMS)} I _{TSM}	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{lead} \le 66 ^{\circ}\text{C}$ full sine wave; $T_{j} = 25 ^{\circ}\text{C}$ prior to surge	-	,	1	А
		t = 20 ms t = 16.7 ms	-		2.5 3.7	Α Δ
l²t dl _⊤ /dt	I ² t for fusing Repetitive rate of rise of on-state current after	t = 10.7 m/s t = 10 ms $I_{TM} = 1.5 \text{ A}; I_G = 0.2 \text{ A};$ $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$	-		78	A A ² s
	triggering	T2+ G+ T2+ G- T2- G- T2- G+	-	5 5	0 0 0 0	A/μs A/μs A/μs A/μs
$ \begin{vmatrix} I_{GM} \\ P_{GM} \\ P_{G(AV)} \\ T_{stg} \\ T_i \end{vmatrix} $	Peak gate current Peak gate power Average gate power Storage temperature Junction temperature	t = 2 μs max t = 2 μs max over any 20 ms period	- - -40 -	0 15	2 5 .1 50 25	Ä W W °C °C

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¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 3 A/µs.

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-lead}	Thermal resistance	full cycle	-	-	60	K/W
	junction to lead	half cycle	-		80	K/W
$R_{th j-a}$	Thermal resistance junction to ambient	pcb mounted;lead length = 4mm	-	150	-	K/W

STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	M	ΑX	UNIT
			BT131-			D	Е	
I _{GT}	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$	T2+ G+ T2+ G- T2- G-			5 5 7	10 10 10	mA mA mA
I _L	Latching current Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$ $V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	T2- G+ T2+ G+ T2+ G- T2- G- T2- G+	-	- - - - 1.3	7 10 20 10 10	10 15 25 15 15	mA mA mA mA mA
V _T V _{GT}	On-state voltage Gate trigger voltage	$I_T = 1.4 \text{ A}$ $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$ $V_D = 400 \text{ V}; I_T = 0.1 \text{ A};$ $I_T = 125 \text{ °C}$		- 0.2	1.2 0.7 0.3	1.	.5 .5	\ \ \ \
I _D	Off-state leakage current	$V_D = V_{DRM(max)}$; $T_j = 125$	°C	-	0.1	0.	.5	mA

DYNAMIC CHARACTERISTICS

T_i = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MI	N.	TYP.	MAX.	UNIT
dV _{com} /dt	Critical rate of rise of commutation voltage	$V_D = 400 \text{ V}; T_i = 125 ^{\circ}\text{C};$ $dI_{com}/dt = 0.5 \text{ A/ms};$	D 3	 5	-	-	V/µs
dV _D /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% \ V_{DRM(max)}; \ T_j = 125 \ ^{\circ}C;$ exponential waveform; $R_{GK} = 1 \ k\Omega$	20	50	-	-	V/μs
t _{gt}	Gate controlled turn-on time	$I_{TM} = 1.5 \text{ A}; V_D = V_{DRM(max)}; I_G = 0.1 \text{ A};$ $dI_G/dt = 5 \text{ A}/\mu \text{s}$		-	2	-	μs

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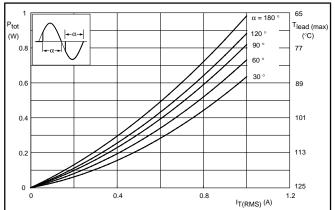


Fig.1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where $\alpha =$ conduction angle.

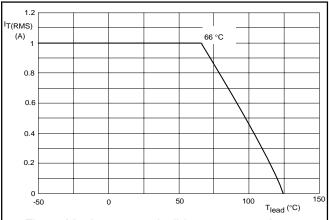


Fig.4. Maximum permissible rms current $I_{\text{T(RMS)}}$, versus lead temperature T_{lead} .

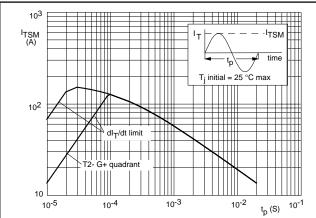


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \le 20$ ms.

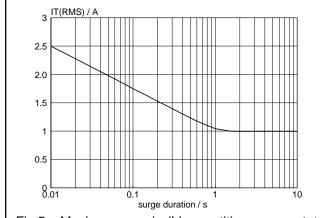


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{lead} \le 66$ °C.

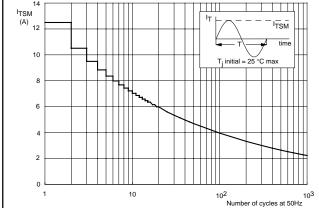


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, f = 50 Hz.

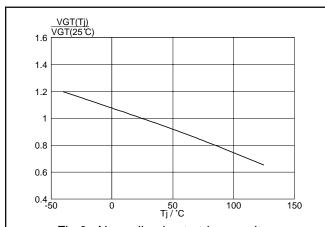
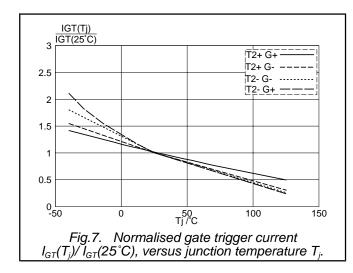
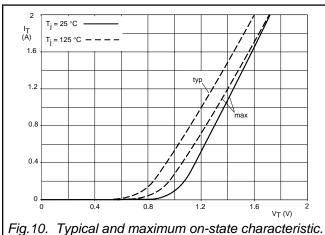


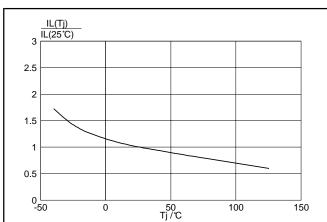
Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)/V_{GT}(25^{\circ}C)$, versus junction temperature T_j .

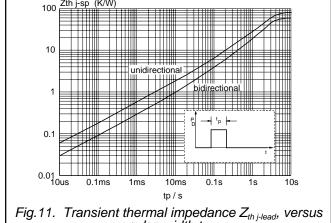
Triacs logic level

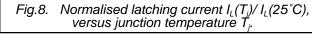
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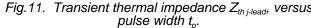


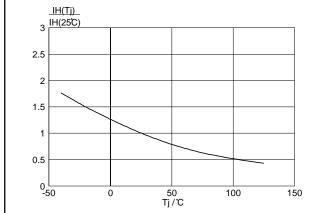












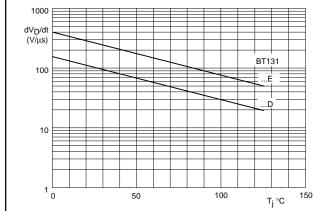
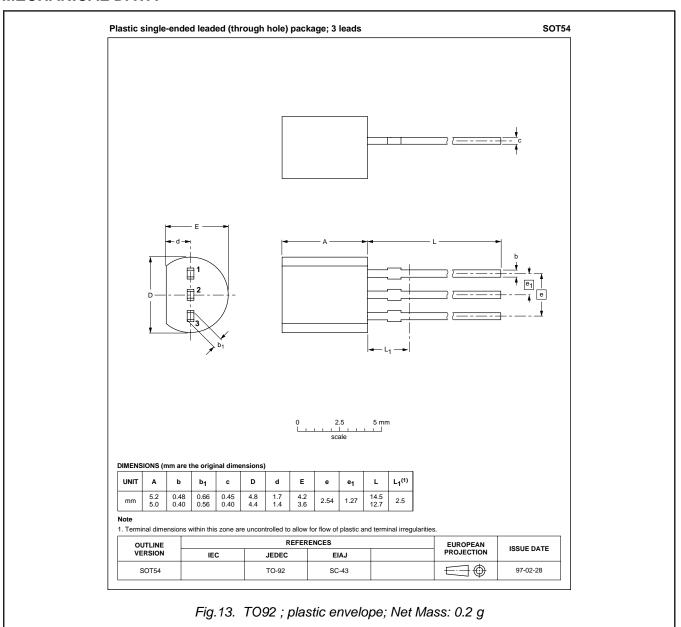


Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}\text{C})$, versus junction temperature T_j .

Fig.12. Minimum, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature $T_{j\cdot}$

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MECHANICAL DATA



Notes

1. Epoxy meets UL94 V0 at 1/8".

Philips Semiconductors Product specification

Triacs logic level

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DEFINITIONS

DATA SHEET STATUS						
DATA SHEET STATUS ²	PRODUCT STATUS ³	DEFINITIONS				
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice				
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product				
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A				

Limiting values

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

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